

Search Notes

Application/Control No.

10/780,884

Examiner

Naum B. Levin

Applicant(s)/Patent under
Reexamination

GOODWIN, FRANCIS

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	19-21	5/10/2005	N L
430	5,22	5/10/2005	N L
356	401	5/10/2005	N L

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
716	19	5/10/2005	N L
716	20	5/10/2005	N L
716	21	5/10/2005	N L

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
overlay, error, correct\$, systematic, non correct\$, non systematic, mark, measur\$, wafer, shift, set, subset.	5/10/2005	N L